

Search Notes

Application/Control No.

10/825,503

Examiner

David E. Bochna

Applicant(s)/Patent under
Reexamination

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Art Unit

3679

SEARCHED

Class	Subclass	Date	Examiner
285	7	12/6/2006	DB
	184		
	273		
	282		
15	410		
	351		

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR